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Gunes, M.; Thornton, M.A.; Kocan, F.; Szygenda, S.A.;
[Circuits and Systems, 2005. 48th Midwest Symposium on](#)
August 7-10, 2005 Page(s):744 - 749
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4. Delay and power calculation standards - Part 3: Standard Delay Format (SDF) for the electro
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2004 Page(s):0_1 - 94

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5. IEEE standard for standard delay format (SDF) for the electronic design process
IEEE Std 1497-2001
14 Dec. 2001

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6. IEEE standard for integrated circuit (IC) delay and power calculation system
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